INFRARED EMITTING DIODES

LHIR13743-T50/TBF-X

DATA SHEET

DOC. NO: QW0905-LHIR13743-T50/TBF-X

REV. : <u>B</u>

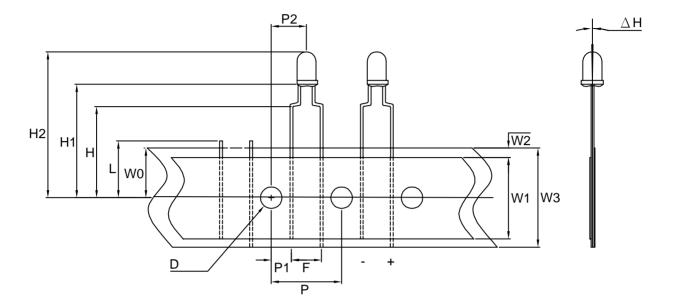
DATE : 08 - Jun. - 2006



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Package Dimensions

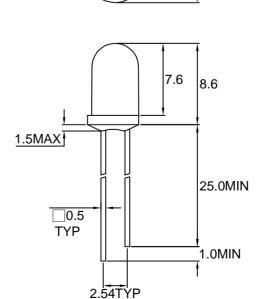




Note: 1.All dimension are in millimeter tolerance is ± 0.25 mm unless otherwise noted.

2. Specifications are subject to change without notice.

LHIR13743-T50



5.0

5.9



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Features:

- 1. High radiant intensity.
- 2. Suitable for pulse applications.
- 3. Low average degradation.

Descriptions:

The LHIR13743-T50/TBF-X series are super-high efficiency Gallium Aluminum Arsenide infrared emitting diodes encapsulated in water clear plastic T-1 3/4 package individually

Device Selection Guide:

PART NO	MATERIAL	LENS COLOR	
LHIR13743-T50/TBF-X	AlGaAs/GaAs	Water Clear	



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Absolute Maximum Ratings at Ta=25 °C

Parameter	Symbol	Ratings	LINIT
Parameter		HIR	UNIT
Forward Current	lF	50	mA
Peak Forward Current (300PPS,10 μs Pulse)	lfp	1	А
Power Dissipation	PD	100	mW
Reverse Voltagev	Vr	5	V
Electrostatic Discharge	ESD	2000	V
Operating Temperature	Topr	-40 ~ +85	°C
Storage Temperature	Tstg	-40 ~ +85	$^{\circ}\!\mathbb{C}$

Electrical Optical Characteristics (Aa=25°C)

PARAMETER	SYMBOL	Min.	Тур.	Max.	UNIT	TEST CONDITION
Radiant Intensity	Le	6.0	12.5		mW/sr	IF=50mA
Aperture Radiant Incidence	Ee	1.0	1.8		mW/cm²	IF=50mA
Peak Wavelength	λ peak		850		nm	IF=20mA
Spectral Line Half Width	Δλ		50		nm	IF=20mA
Forward Voltage	VF		1.5	2.0	V	IF=50mA
Reverse Current	IR			100	μ A	VR=5V
Viewing Angle	2 <i>θ</i> 1/2		60		deg	

Note : 1.The forward voltage data did not including $\pm 0.1 \text{V}$ testing tolerance.

2. The radiant intensity data did not including $\pm 15\%$ testing tolerance.



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• Dimension Symbol Information

		SYMBOL	SPECIFICATIONS			
SYMBOL ITEMS	OPTION CODE		Minimum		Maximum	
			mm	inch	mm	inch
Tape Feed Hole Diameter		D	3.8	0.15	4.2	0.17
Component Lead Pitch		F	4.8	0.19	5.8	0.23
Front-To-Rear Deflection		ΔΗ			2.0	0.08
Height Of Seating Plane		Н	15.5	0.61	16.5	0.65
	TBF-1		17.5	0.69	19.5	0.77
	TBF-2		19.0	0.75	21.0	0.83
	TBF-3]	22.5	0.89	24.5	0.96
	TBF-4		25.5	1.0	26.5	1.04
	TBF-5		21.5	0.85	22.5	0.89
	TBF-6		20.2	8.0	21.2	0.83
	TBF-7		17.125	0.67	21.125	0.83
	TBF-8	1	20.0	0.79	22.5	0.89
Feed Hole To Bottom Of Component	TBF-9		26	1.02	28	1.10
	TBF-10	H1	18.8	0.74	19.8	0.78
	TBF-11		24.0	0.94	26.0	1.02
	TBF-12	1	21.0	0.83	23.0	0.91
	TBF-13		19.0	0.75	20.0	0.79
	TBF-14		21.7	0.85	23.7	0.93
	TBF-15		22.5	0.89	23.5	0.93
	TBF-16		17.5	0.69	18.0	0.71
	TBF-17		18.5	0.73	19.5	0.77
	TBF-18		20.5	0.81	21.5	0.85
Feed Hole To Overall Component Height		H2			36	1.42
Lead Length After Component Height		L	W	/0	11	0.43
Feed Hole Pitch		Р	12.4	0.49	13	0.51
Lead Location		P1	3.15	0.12	4.55	0.18
Center Of Component Location		P2	5.1	0.2	7.7	0.3
Overall Taped Package Thickness		Т			1.42	0.06
Feed Hole Location		W0	8.5	0.33	9.75	0.38
Adhesive Tape Width		W1	14.5	0.57	15.5	0.61
Adhesive Tape Position		W2	0	0	4.0	0.16
Tape Width		W3	17.5	0.69	19	0.75

REMARK:TBF = Tape And Box Forming Leads

Symbol

L

W

Н

· Dimensions Symbol Information

Description

Overall Length

Overall Width

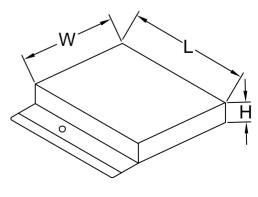
Overall Thickness

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Specification						
minimum maxmum						
mm	inch	inch mm inch				
330	13.0	340	13.4			
265	10.4	275	10.8			
50	1.97	60	2.4			
Quantity/Boy						

Part No.	Quantity/Box
LHIR13743-T50/TBF-X	2000PCS

Package Dimensions





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Typical Electro-Optical Characteristics Curve

HIR CHIP

Relative Radiant Power

Fig.1 Forward Current vs. Rorward Voltage

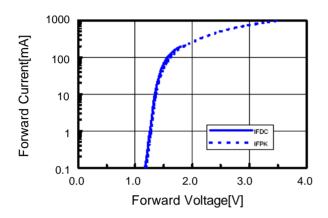


Fig.2 Relative Radiant Power vs. Wavelength

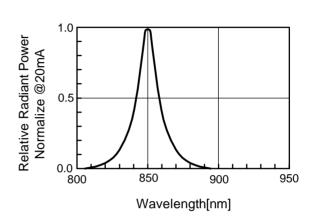


Fig.3 Relative Radiant Power vs. Forward DC Current

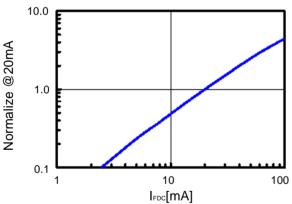


Fig.4 Relative Radiant Power

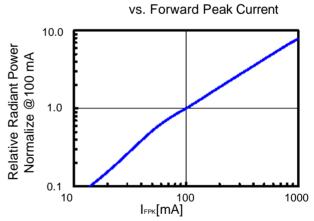


Fig.5 Forward DC Voltage vs. Temperature

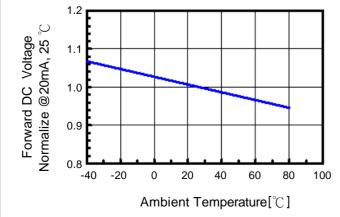
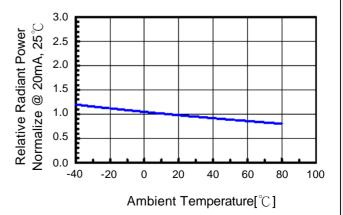


Fig.6 Relative Radiant Power vs. Temperature





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Storage time:

- 1.The operation of Temperatures and RH are : 5 $^{\circ}$ C ~35 $^{\circ}$ C ,RH<60%.
- 2.Once the package is opened, the products should be used within a week. Otherwise, they should be kept in a damp proof box with descanting agent. Considering the tape life, we suggest our customers to use our products within a year(from production date).
- 3.If opened more than one week in an atmosphere 5 $^{\circ}$ C ~ 35 $^{\circ}$ C, RH<60%, they should be treated at 60 $^{\circ}$ C±5 $^{\circ}$ C fo r 15hrs.

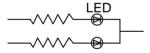
Drive Method:

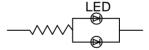
LED is a current operated device, and therefore, require some kind of current limiting incorporated into the driver circuit. This current limiting typically takes the form of a current limiting resistor placed in series with the LED.

Consider worst case voltage variations than could occur across the current limiting resistor. The forwrd current should not be allowed to change by more than 40 % of its desired value.

Circuit model A

Circuit model B





- (A) Recommended circuit.
- (B) The difference of brightness between LED could be found due to the VF-IF characteristics of LED.

Cleaning:

Use alcohol-based cleaning solvents such as isopropyl alcohol to clean the LED.

ESD(Electrostatic Discharge):

Static Electricity or power surge will damage the LED. Use of a conductive wrist band or anti-electrosatic glove is recommended when handing these LED. All devices, equipment and machinery must be properly grounded.

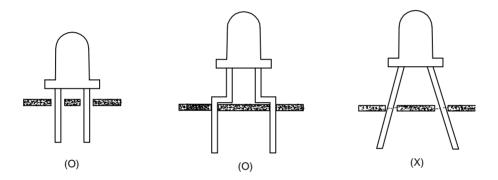


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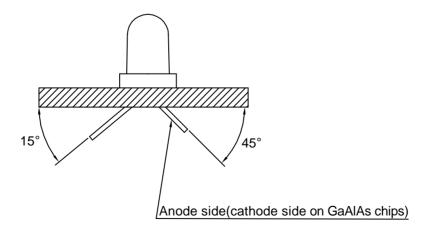
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Mounting:

 If the leads are subjected to stress during soldering a printed circuit board, illumination failure may result immediately or later during use. For this reason, make sure that the intervals between the installation holes in the board are equal to the intervals between the leads (after forming if done) so that no stress is applied to the lead.



 The LED lamps are designed for high-density mounting and have a structure which can alleviate mechanical stress due to clinching. Nevertheless, take care to avoid the occurrence of residual mechanical stress due to clinching.





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Reliability Test:

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=20mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and themal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 ℃±5℃ 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 °C ±5 °C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 °C ±5 °C 2.RH=90 %~95 % 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 °C ±5 °C &-40 °C ±5 °C (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 °C ±5 °C 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 °C±5 °C 2.Dwell time=5±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2